

STL18N55M5

N-channel 550 V, 0.205 Ω 13 A PowerFLAT™ 8x8 HV MDmesh™ V Power MOSFET

Features

Туре	V _{DSS} @ T _{Jmax}	R _{DS(on)} max	I _D
STL18N55M5	600 V	< 0.270 Ω	13 A ⁽¹⁾

- 1. The value is rated according to $R_{\mbox{\scriptsize thj-case}}$
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Application

■ Switching applications

Description

This device is an N-channel MDmesh™ V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

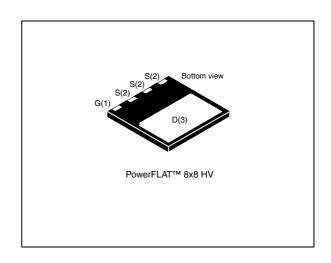


Figure 1. Internal schematic diagram

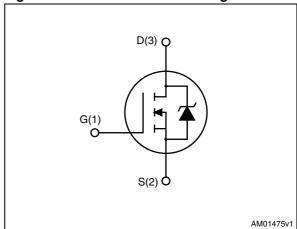


Table 1. Device summary

Order code	Marking	Package	Packaging
STL18N55M5	18N55M5	PowerFLAT™ 8x8 HV	Tape and reel

Contents STL18N55M5

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STL18N55M5 Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	550	V
V _{GS}	Gate-source voltage	± 25	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	13	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	8	Α
I _{DM} (1),(2)	Drain current (pulsed)	52	Α
I _D ⁽³⁾	Drain current (continuous) at T _{amb} = 25 °C	2.4	Α
I _D (3)	Drain current (continuous) at T _{amb} = 100 °C	1.5	Α
I _{DM} ^{(2),(3)}	Drain current (pulsed)	9.6	Α
P _{TOT} (3)	Total dissipation at T _{amb} = 25 °C	3	W
P _{TOT} ⁽¹⁾	Total dissipation at T _C = 25 °C	90	W
I _{AR}	Avalanche current, repetitive or not- repetitive (pulse width limited by T _j max)	4	А
E _{AS}	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V)	200	mJ
dv/dt (4)	Peak diode recovery voltage slope	15	V/ns
T _{stg}	Storage temperature	- 55 to 150	°C
Tj	Max. operating junction temperature	150	°C

^{1.} The value is rated according to $R_{\mbox{\scriptsize thj-case}}$

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	1.38	°C/W
R _{thj-amb} ⁽¹⁾	Thermal resistance junction-amb max	45	°C/W

^{1.} When mounted on 1inch² FR-4 board, 2 oz Cu

^{2.} Pulse width limited by safe operating area

^{3.} When mounted on FR-4 board of inch², 2oz Cu

^{4.} $I_{SD} \leq$ 13 A, di/dt \leq 400 A/ μ s, $V_{Peak} < V_{(BR)DSS}$, V_{DD} =400 V

Electrical characteristics STL18N55M5

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	550			V
I _{DSS}	Zero gate voltage drain current	V _{DS} = 550 V V _{DS} = 550 V, T _C =125 °C V _{GS} = 0			1 100	μA μA
I _{GSS}	Gate-body leakage current	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0$			100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 6 A		0.205	0.270	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 100 V, f = 1 MHz, V _{GS} = 0	-	1352 38 3.7	-	pF pF pF
C _{o(tr)} ⁽¹⁾	Equivalent capacitance time related	$V_{DS} = 0$ to 440 V, $V_{GS} = 0$	-	98	-	pF
C _{o(er)} ⁽²⁾	Equivalent capacitance energy related		-	35	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz open drain	-	1.7	-	Ω
Qg	Total gate charge	$V_{DD} = 440 \text{ V}, I_{D} = 6.5 \text{ A},$		31		nC
Q_{gs}	Gate-source charge	V _{GS} = 10 V	-	6.3	-	nC
Q_{gd}	Gate-drain charge	(see Figure 15)		14		nC

^{1.} $C_{oss\,eq.}$ time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

^{2.} $C_{oss\ eq.}$ energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t _{d(off)}	Turn-off delay time	$V_{DD} = 400 \text{ V}, I_{D} = 9\text{A},$		29		ns
t _{r(V)}	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$		9.5		ns
t _{c(off)}	Cross time	(see Figure 16),	-	23	-	ns
t _{f(i)}	Fall time	(see Figure 19)		13		ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)		-		13 52	A A
V _{SD} (2)	Forward on voltage	I _{SD} = 13 A, V _{GS} = 0	-		1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 13 A, di/dt = 100 A/μs V _{DD} = 60 V (see <i>Figure 16</i>)	-	238 2.8 23.5		ns µC A
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 13 \text{ A, di/dt} = 100 \text{ A/µs}$ $V_{DD} = 60 \text{ V, T}_j = 150 ^{\circ}\text{C}$ (see <i>Figure 16</i>)	-	278 3.3 24		ns μC A

^{1.} Pulse width limited by safe operating area

^{2.} Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

Electrical characteristics STL18N55M5

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

Figure 3. Thermal impedance

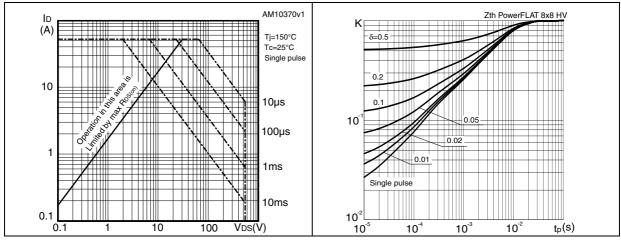


Figure 4. Output characteristics

Figure 5. Transfer characteristics

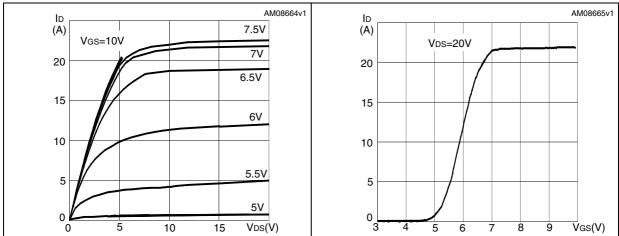


Figure 6. Gate charge vs gate-source voltage Figure 7. Static drain-source on resistance

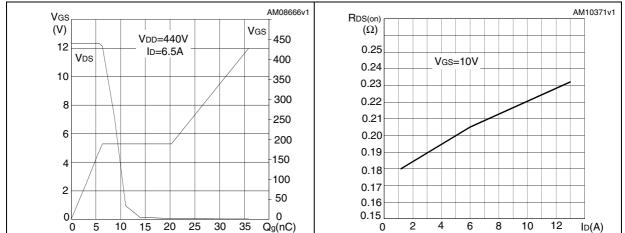


Figure 8. Capacitance variations

Figure 9. Output capacitance stored energy

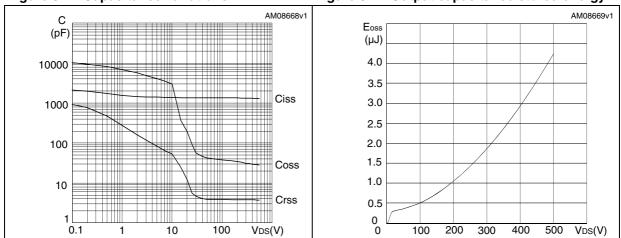


Figure 10. Normalized gate threshold voltage Figure 11. Normalized on resistance vs vs temperature temperature

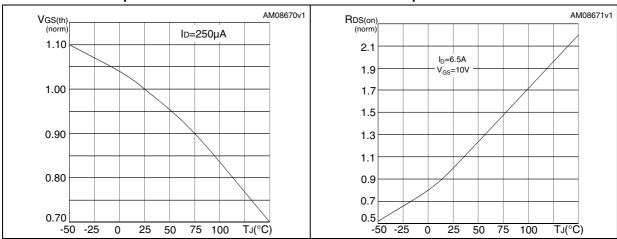
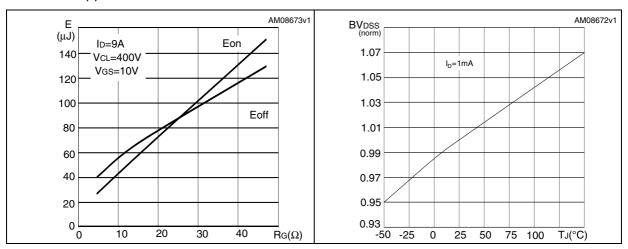


Figure 12. Switching losses vs gate resistance Figure 13. Normalized B_{VDSS} vs temperature



1. Eon including reverse recovery of a SiC diode

Test circuits STL18N55M5

3 Test circuits

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

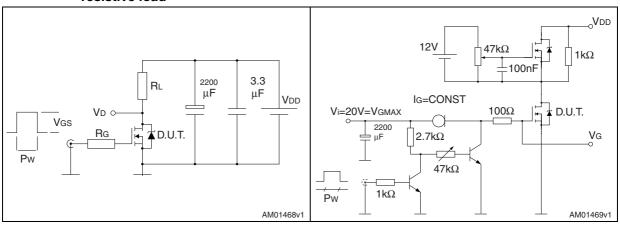


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped inductive load test circuit

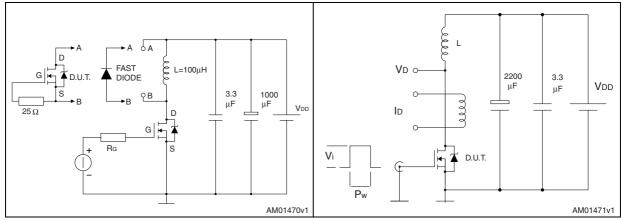
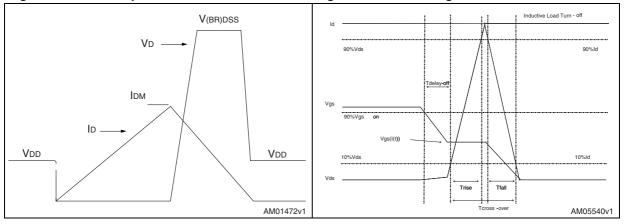


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform



4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Table 8. PowerFLAT™ 8x8 HV mechanical data

Dim.		mm	
Dilli.	Min.	Тур.	Max.
Α	0.80	0.90	1.00
A1	0.00	0.02	0.05
b	0.95	1.00	1.05
D		8.00	
E		8.00	
D2	7.05	7.20	7.30
E2	4.15	4.30	4.40
е		2.00	
L	0.40	0.50	0.60
aaa		0.10	
bbb		0.10	
ccc		0.10	

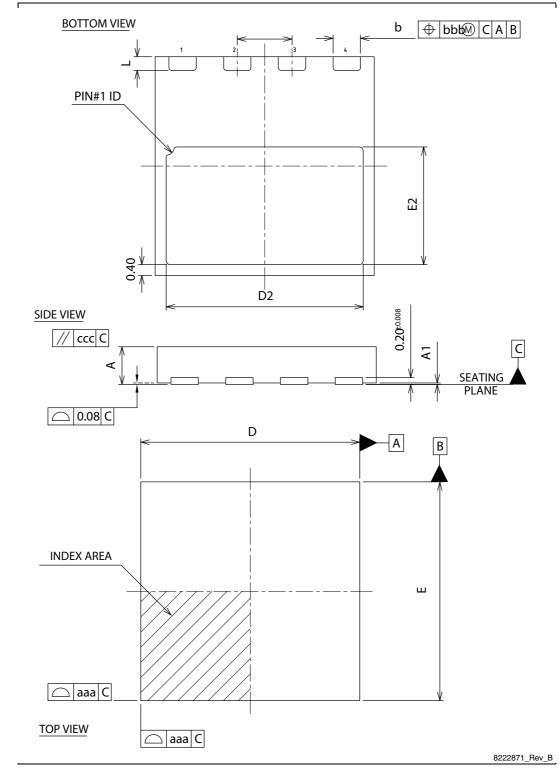


Figure 20. PowerFLAT™ 8x8 HV drawing mechanical data

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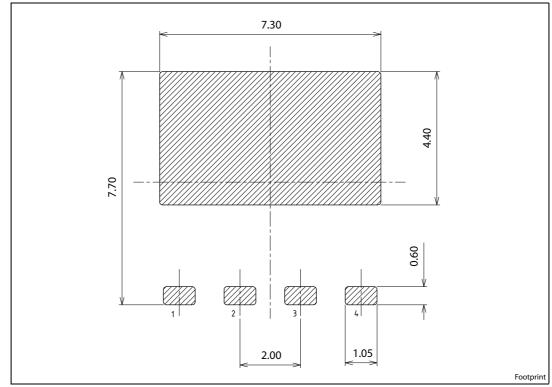


Figure 21. PowerFLAT™ 8x8 HV recommended footprint

12/14 Doc ID 17468 Rev 2

STL18N55M5 Revision history

5 Revision history

Table 9. Document revision history

Date	Revision	Changes
03-May-2010	1	First release
04-Oct-2011	2	Section 4: Package mechanical data has been updated Document status promoted from preliminary data to datasheet Inserted new section: Electrical characteristics (curves) Minor text changes.

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